


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530307	<b>Applicant(s)/Patent Under Reexamination</b>  BHAT ET AL.
	<b>Examiner</b>  Lee, Siu M	<b>Art Unit</b>  2611

SEARCHED			
Class	Subclass	Date	Examiner
375	148, 316, 345, 346	11/06/2007	Siu M. Lee

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	11/06/07	Siu M. Lee
Discuss the application with Chieh Fan	11/06/07	Siu M. Lee
EAST	10/13/2008	Siu M. Lee
Discuss the application with Chieh Fan	10/14/2008	Siu M. Lee

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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